

## 2024 European Test Symposium - Program at a Glance

Day/Time	MONDAY - May 20	TUESDAY - May 21	WEDNESDAY - May 22	THURSDAY - May 23	FRIDAY - May 24
8:00			Conference Registration	Conference Registration	
8:15					
8:30		Conference Registration	KEYNOTE 2: Sustainability and the Outlook of Semiconductor Industry <i>Cheng-Wen Wu - STUST (TW)</i>	KEYNOTE 3: It's all about trust - The road to autonomous driving will connect test, reliability and safety <i>Juergen Alt - Infineon Technologies (DE)</i>	Workshop Registration
8:45					
9:00		CONFERENCE OPENING			
9:15			REGULAR Session 4: Analog and Mixed-Signal Test	Embedded TUTORIAL 1: SDCs in Computing Systems: Early Predictions and Large-Scale Measurements	
9:30		KEYNOTE 1: Silent Data Corruption Errors in VLSI Circuits <i>Rama Govindaraju - Google (US)</i>	Embedded TUTORIAL 2: Lifecycle Management of Emerging Memories	Embedded TUTORIAL 3: Approximate Fault Tolerant Systems	SPECIAL Session 4: Test-Fleet Optimization Using ML
9:45				Embedded TUTORIAL 4: SDC from Timing Marginalities due to Process Variations	
10:00					
10:15		COFFEE BREAK Scientific Poster Session 1	COFFEE BREAK PhD Forum Poster Session 2 & McCluskey Thesis Poster Session		COFFEE BREAK Scientific Poster Session 2 & EU Projects Poster Session
10:30					
10:45					
11:00		REGULAR Session 1: Test Generation and Compression	INDUSTRIAL Session 1: AMS and RF Test	SPECIAL Session 1: Reliability and Security of AI Hardware	
11:15			REGULAR Session 5: Reliability Analysis and Monitoring	INDUSTRIAL Session 3: Memory Test	McCluskey PhD Thesis Competition
11:30					REGULAR Session 6: Hardware Security
11:45					INDUSTRIAL Session 4: Panel
12:00					SPECIAL Session 5: Testing for Reliability of Modern Power Electronic Components
12:15					
12:30					
12:45					
13:00		LUNCH BREAK	LUNCH BREAK	LUNCH BREAK	
13:15	Conference Registration				
13:30					
13:45					
14:00					
14:15		REGULAR Session 2: AI in Test and Security	PhD Forum Session	SPECIAL Session 2: Silent Data Corruption - Test or Reliability Problem?	
14:30	TSS @ETS Tutorial 1: Silicon Fault Analysis (FA) equipment for security analysis			PANEL	
14:45	TSS @ETS Tutorial 2: Security of Generative AI and Generative AI for Security				REGULAR Session 7: Test and Verification in Emerging Circuits
15:00					INDUSTRIAL Session 5: Reliability and Test Development
15:15					SPECIAL Session 6: IEEE Std P3405: New Standard-under-Development for Chiplet Interconnect Test and Repair
15:30					
15:45					
16:00		COFFEE BREAK PhD Forum Poster Session 1 & Industrial Poster Session			CONFERENCE CLOSING & STUDENT AWARDS
16:15	COFFEE BREAK				COFFEE BREAK
16:30		REGULAR Session 3: Design for Test and Trust	INDUSTRIAL Session 2: Vendor Presentations	SPECIAL Session 3: What would interactive testing with 1687 look like?	
16:45					
17:00	TSS @ETS Tutorial 1: Silicon Fault Analysis (FA) equipment for security analysis				AI-TREATS Workshop
17:15	TSS @ETS Tutorial 2: Security of Generative AI and Generative AI for Security				eARTS Workshop
17:30					CITaR Workshop
17:45					
18:00		BREAK			
18:15					
18:30	BREAK				
18:45		Wine & Cheese PANEL			
19:00	ETS'24 WELCOME RECEPTION		SOCIAL EVENT (16:30 - 22:00)		Workshops WELCOME RECEPTION
19:15					
19:30					
19:45					
20:00					
20:15					

PLENARY Sessions	REGULAR Sessions	INDUSTRIAL Sessions	SPECIAL Sessions	EMBEDDED Tutorials	STUDENT Activities	WORKSHOPS
------------------	------------------	---------------------	------------------	--------------------	--------------------	-----------